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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/701,082	UEDA ET AL.	
Examiner	Art Unit	
Tan V. Mai	2193	

SEARCHED					
Class	Subclass	Date	Examiner		
708	3, 250, 255, 801	4/20/2007	MAI		
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INTERFERENCE SEARCHED					
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(INCLUDING SEARCI	TSIRAIEGI)	
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Inventor(s) search Double Patent Check Data Bases Search (see search history printout(s))	4/20/2007	MAI	
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